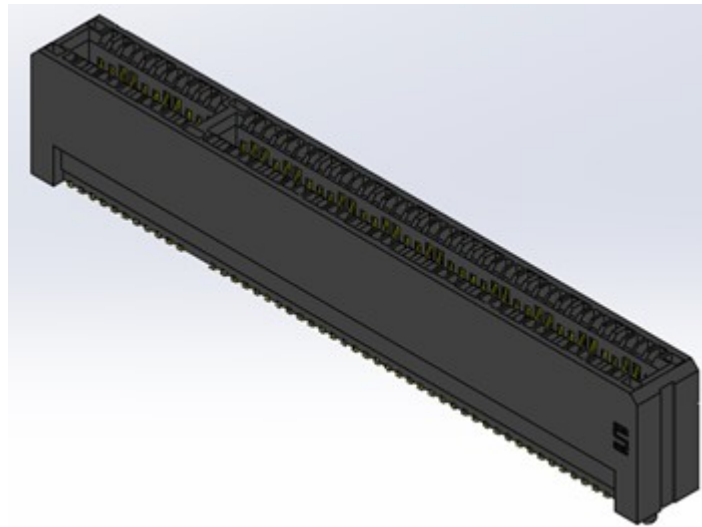
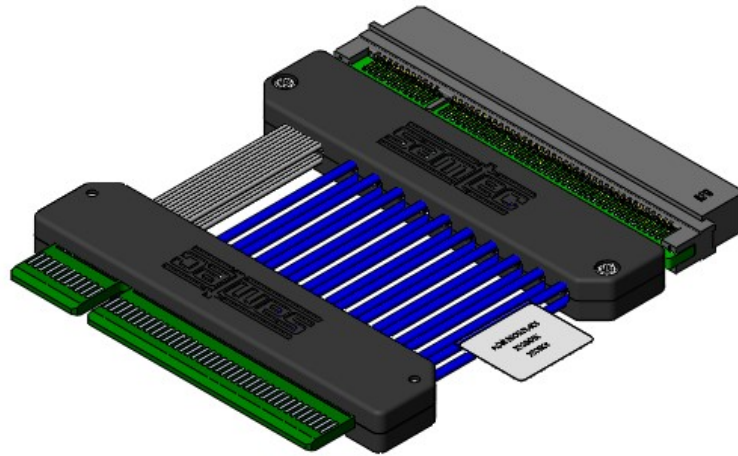




| | |
|---|---------------------------------------|
| Project Number: Design Qualification Test Report | Tracking Code: CR-980401_Report_Rev_1 |
| Requested by: Leo Lee | Date: 12/28/2023 |
| Part #: PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT | |
| Part description: PCIEC/PCIE | Tech: Kason He |
| Test Start: 9/6/2023 | Test Completed: 9/25/2023 |



DESIGN QUALIFICATION TEST REPORT

PCIEC/PCIE
PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT

REVISION HISTORY

| DATA | REV.NUM. | DESCRIPTION | ENG |
|-------------|-----------------|--------------------|------------|
| 12/28/2023 | 1 | Initial Issue | KH |

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead free
- 9) Samtec Test PCBs used: PCB-111954-TST/PCB-111955-TST/PCB-111956-TST.

FLOWCHARTS

IR/DWV

Pin-to-Pin

| <u>Group 1</u> | | <u>Group 2</u> | | <u>Group 3</u> | | <u>Group 4</u> | |
|--|-------------------|---|-------------------|---|-------------------|--|-------------------------|
| PCIEC-G5-164-0400-M1-P-85 PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | | PCIEC-G5-164-0400-M1-P-85 2 Assemblies | | PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | | PCIEC-G5-164-0400-M1-P-85 PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | |
| Step | Description | Step | Description | Step | Description | Step | Description |
| 1. | DWV Breakdown (2) | 1. | DWV Breakdown (2) | 1. | DWV Breakdown (2) | 1. | IR (4) |
| | | | | | | 2. | DWV at Test Voltage (1) |
| | | | | | | 3. | Thermal Shock (5) |
| | | | | | | 4. | IR (4) |
| | | | | | | 5. | DWV at Test Voltage (1) |
| | | | | | | 6. | Humidity (3) |
| | | | | | | 7. | IR (4) |
| | | | | | | 8. | DWV at Test Voltage (1) |

Row-to-Row

| <u>Group 5</u> | | <u>Group 6</u> | | <u>Group 7</u> | | <u>Group 8</u> | |
|--|-------------------|---|-------------------|---|-------------------|--|-------------------------|
| PCIEC-G5-164-0400-M1-P-85 PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | | PCIEC-G5-164-0400-M1-P-85 2 Assemblies | | PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | | PCIEC-G5-164-0400-M1-P-85 PCIE-G5-16-01-L-DP-A-WT 2 Assemblies | |
| Step | Description | Step | Description | Step | Description | Step | Description |
| 1. | DWV Breakdown (2) | 1. | DWV Breakdown (2) | 1. | DWV Breakdown (2) | 1. | IR (4) |
| | | | | | | 2. | DWV at Test Voltage (1) |
| | | | | | | 3. | Thermal Shock (5) |
| | | | | | | 4. | IR (4) |
| | | | | | | 5. | DWV at Test Voltage (1) |
| | | | | | | 6. | Humidity (3) |
| | | | | | | 7. | IR (4) |
| | | | | | | 8. | DWV at Test Voltage (1) |

- (1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds
- (2) DWV Breakdown = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds
- (3) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b
- (4) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max
- (5) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued**Current Carrying Capacity**Group 1

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
2 Pins Powered
Signal

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Number of Positions = 1 Rows = 2 |

Group 2

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
4 Pins Powered
Signal

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Number of Positions = 2 Rows = 2 |

Group 3

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
6 Pins Powered
Signal

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 3 |

Group 4

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
8 Pins Powered
Signal

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 4 |

Group 5

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
66 Pins Powered
Signal

| Step | Description |
|------|--|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 33 |

Group 6

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
2 Pins Powered
Power

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 1 |

Group 7

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
4 Pins Powered
Power

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 2 |

Group 8

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
6 Pins Powered
Power

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 3 |

Group 9

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
8 Pins Powered
Power

| Step | Description |
|------|---|
| 1. | CCC ⁽²⁾ Rows = 2 Number of Positions = 4 |

Group 10

PCIEC-G5-164-0400-M1-P-85
PCIE-G5-16-01-L-DP-A-WT
All Power

| Step | Description |
|------|--------------------------------|
| 1. | CCC - All Power ⁽¹⁾ |

(1) CCC - All Power = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

(2) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

FLOWCHARTS Continued**Cable Pull**Group 1

PCIEC-G5-164-0400-M1-P-85

5 Assemblies
90 Degrees

| Step | Description |
|------|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |

Group 2

PCIEC-G5-036-0400-M1-P-85

5 Assemblies
90 Degrees

| Step | Description |
|------|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |

Group 3

PCIEC-G5-064-0400-M1-P-85

5 Assemblies
90 Degrees

| Step | Description |
|------|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |

(1) Cable Pull = EIA-364-38

Measure and Record Force Required to Failure
Failure = Discontinuity >1 microsecond at 10 ohms**Cable Flex**Group 1

PCIEC-G5-164-0400-M1-P-85

PCIE-G5-16-01-L-DP-A-WT

8 Assemblies
Flat Cable

| Step | Description |
|------|------------------------------------|
| 1. | IR ⁽³⁾ |
| 2. | DWV at Test Voltage ⁽²⁾ |
| 3. | Cable Flex ⁽¹⁾ |
| 4. | Visual Inspection |
| 5. | IR ⁽³⁾ |
| 6. | DWV at Test Voltage ⁽²⁾ |

(1) Cable Flex = EIA-364-41

Circular Jacket Cable - to be tested 90° each direction (180° total)

Flat Cable - to be tested 70° each direction (140° total)

Monitor continuity during flex testing

Failure = Discontinuity >1 microsecond at 10 ohms

(2) DWV at Test Voltage = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(3) IR = EIA-364-21

Test Condition = 500 Vdc, 2 Minutes Max

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
 - a. Self-heating (resistive)
 - b. Reduction in heat sink capacity affecting the heated contacts.
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at four temperature points are reported:
 - a. Ambient
 - b. 40° C
 - c. 50° C
 - d. 70° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat buildup) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

CABLE PULL:

- 1) Secure cable near center and pull-on connector.
 - a. At 90°, in-line with cable



Fig. 1
90° Connector pull.

CABLE FLEX:

- 1) Oscillate and monitor electrical continuity for open circuit indication.
 - a. $\pm 70^\circ$ Flex Mode, bend up to 500 cycles. load on cable end.



Fig. 1
(Setup picture)

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs.
- 2) MEASUREMENTS/CALCULATIONS
 - a. The breakdown voltage shall be measured and recorded.
 - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
 - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

RESULTS

Temperature Rise, CCC at a 20% de-rating

Signal Pin at Cable

- CCC for a 30°C Temperature Rise-----1.00 A per contact with 2 contacts (2x1) powered.
- CCC for a 30°C Temperature Rise-----0.97 A per contact with 4 contacts (2x2) powered.
- CCC for a 30°C Temperature Rise-----0.89 A per contact with 6 contacts (2x3) powered.
- CCC for a 30°C Temperature Rise-----0.91 A per contact with 8 contacts (2x4) powered.
- CCC for a 30°C Temperature Rise-----0.83 A per contact with 66 contacts (2x33) powered.

Power Pin at Cable

- CCC for a 30°C Temperature Rise-----2.3 A per contact with 2 contacts (2x1) powered.
- CCC for a 30°C Temperature Rise-----1.7 A per contact with 4 contacts (2x2) powered.
- CCC for a 30°C Temperature Rise-----1.5 A per contact with 6 contacts (2x3) powered.
- CCC for a 30°C Temperature Rise-----1.2 A per contact with 8 contacts (2x4) powered.
- CCC for a 30°C Temperature Rise-----1.1 A per contact with 11 contacts powered.

Cable Pull force

PCIEC-G5-164-0400-M1-P-85

- 90° Pull
 - Min ----- 254.45 lbs
 - Max ----- 267.67 lbs

PCIEC-G5-036-0400-M1-P-85

- 90° Pull
 - Min -----62.80 lbs
 - Max -----66.72 lbs

PCIEC-G5-064-0400-M1-P-85

- 90° Pull
 - Min ----- 105.60 lbs
 - Max ----- 116.79 lbs

RESULTS Continued**Insulation Resistance minimums, IR****Pin to Pin**

- **Initial**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000Meg Ω ----- Passed
- **Humidity**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed

Row to Row

- **Initial**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed
- **Thermal Shock**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000Meg Ω ----- Passed
- **Humidity**
 - Mated -----45000 Meg Ω ----- Passed
 - Unmated -----45000 Meg Ω ----- Passed

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
 - Breakdown Voltage -----905 VAC
 - Test Voltage -----680 VAC
 - Working Voltage -----225 VAC

Pin to Pin

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

Row to Row

- **Initial DWV** -----Passed
- **Thermal DWV** -----Passed
- **Humidity DWV** -----Passed

RESULTS Continued

Cable Flex:

Insulation Resistance minimums, IR

Pin to Pin

- **Initial**
 - Mated-----21500 Meg Ω ----- Passed
- **After 500 Flex Cycles**
 - Mated-----34000 Meg Ω ----- Passed

Row to Row

- **Initial**
 - Mated-----45000 Meg Ω ----- Passed
- **After 500 Flex Cycles**
 - Mated-----45000 Meg Ω ----- Passed

Dielectric Withstanding Voltage minimums, DWV

- Test Voltage -----680 VAC

Pin to Pin

- **Initial DWV**-----Passed.
- **After 500 Flex Cycles DWV**----- Passed.

Row to Row

- **Initial DWV**-----Passed.
- **After 500 Flex Cycles DWV**----- Passed.

DATA SUMMARIES

TEMPERATURE RISE (Current Carrying Capacity, CCC):

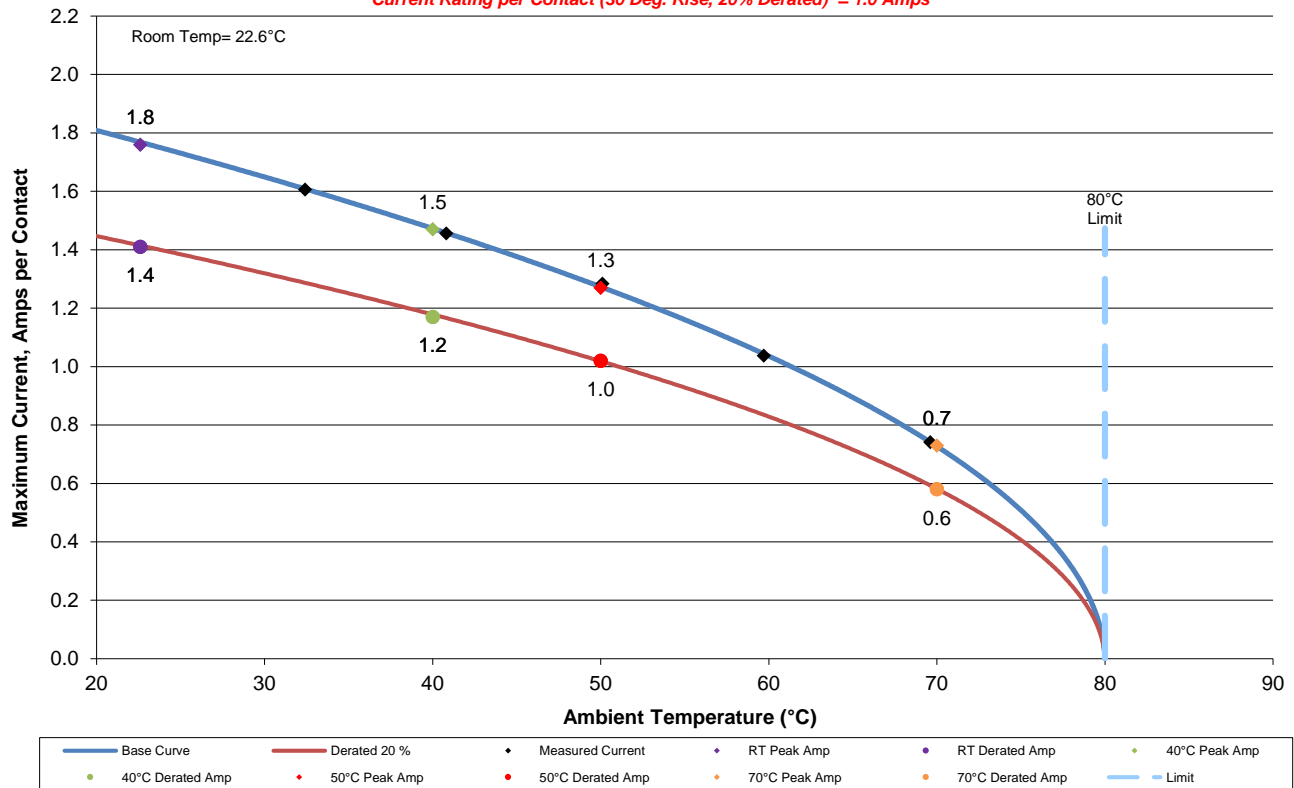
- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer-controlled data acquisition).
- 4) Adjacent contacts were powered:

Signal Pin at Cable

- a. Linear configuration with 2 adjacent conductors/contacts powered.

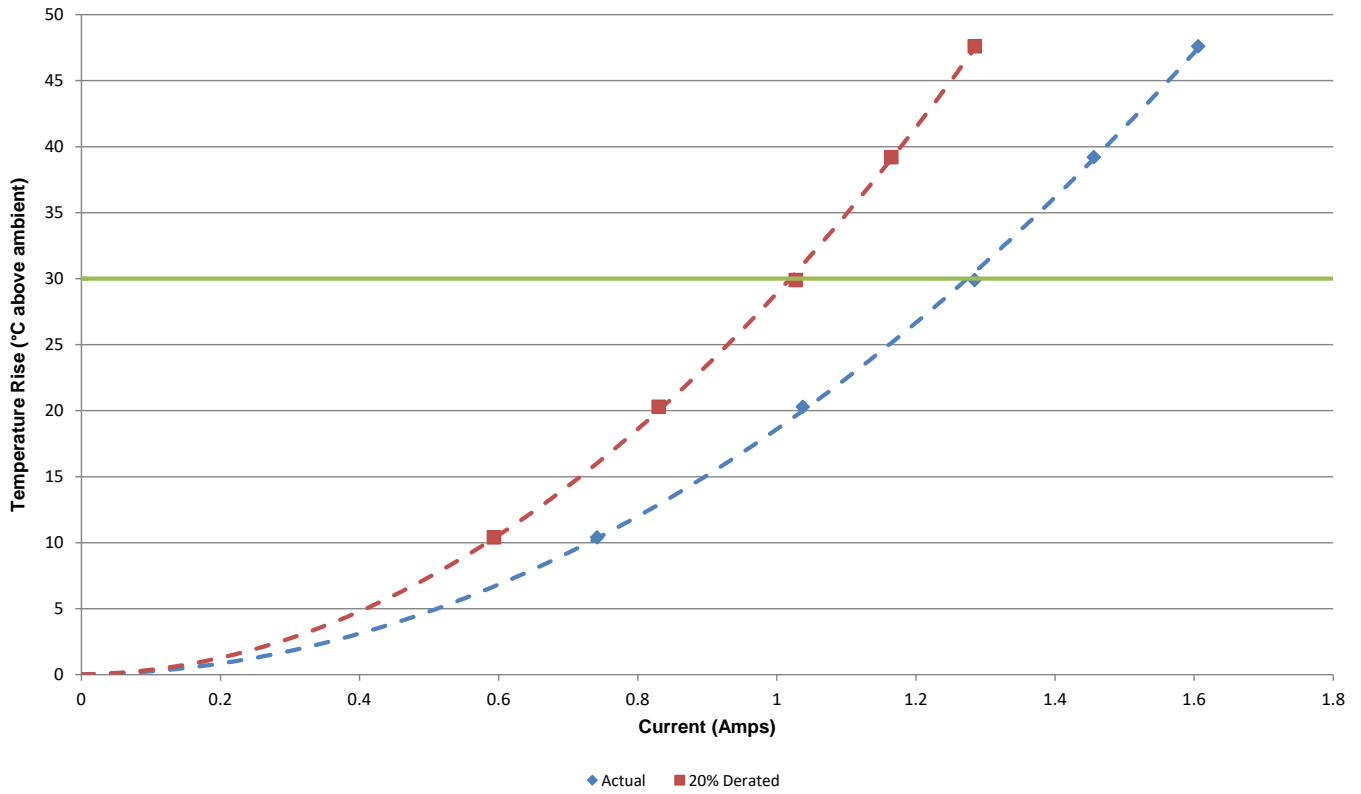
CR-980401
2(2X1) Contacts in Series(Signal Pin Cable)
Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT

Current Rating per Contact (30 Deg. Rise, 20% Derated) = 1.0 Amps



DATA SUMMARIES Continued

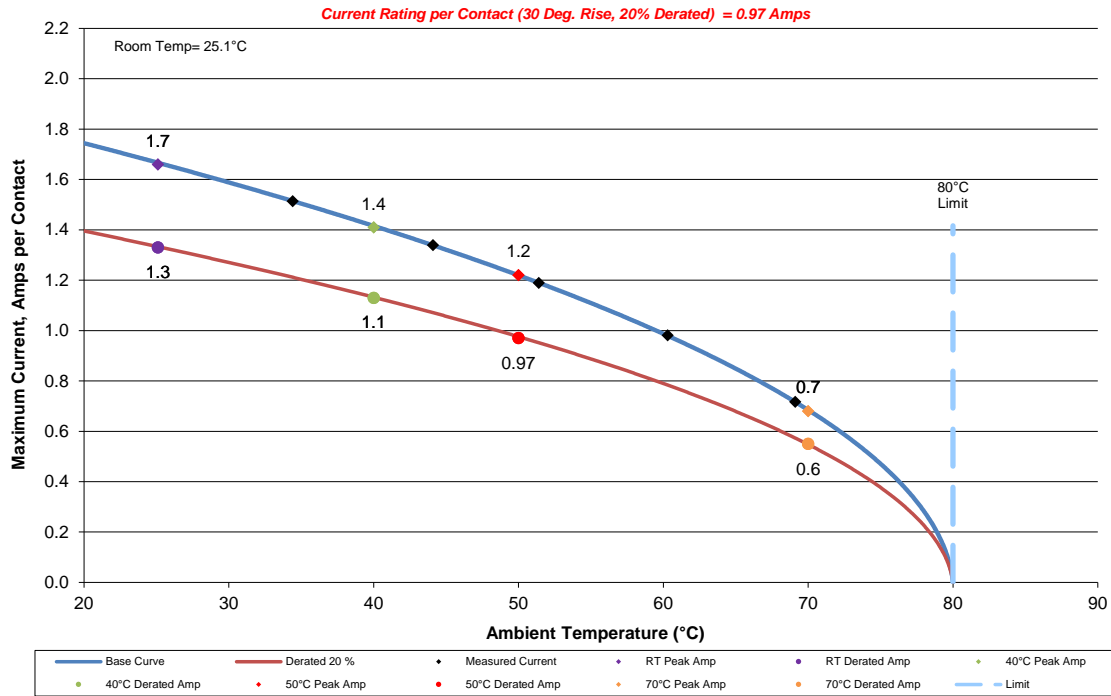
CR-980401
2(2X1) Contacts in Series(Signal Pin Cable)
Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



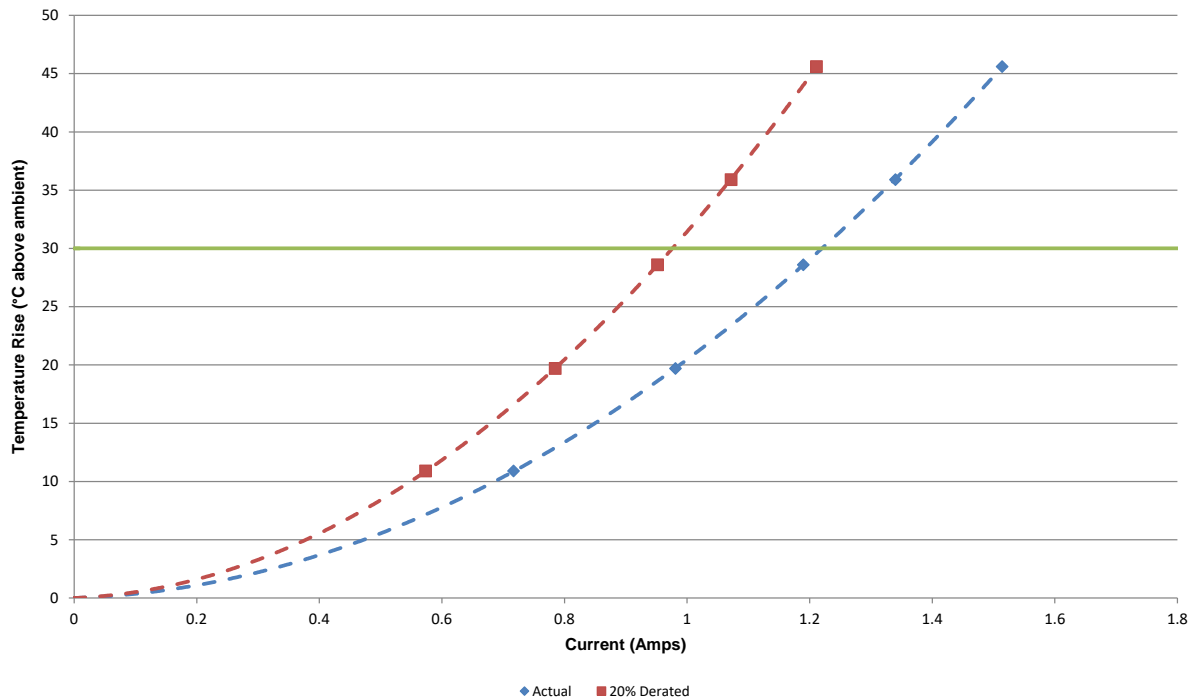
DATA SUMMARIES Continued

b. Linear configuration with 4 adjacent conductors/contacts powered.

CR-980401
 4(2X2) Contacts in Series(Signal Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



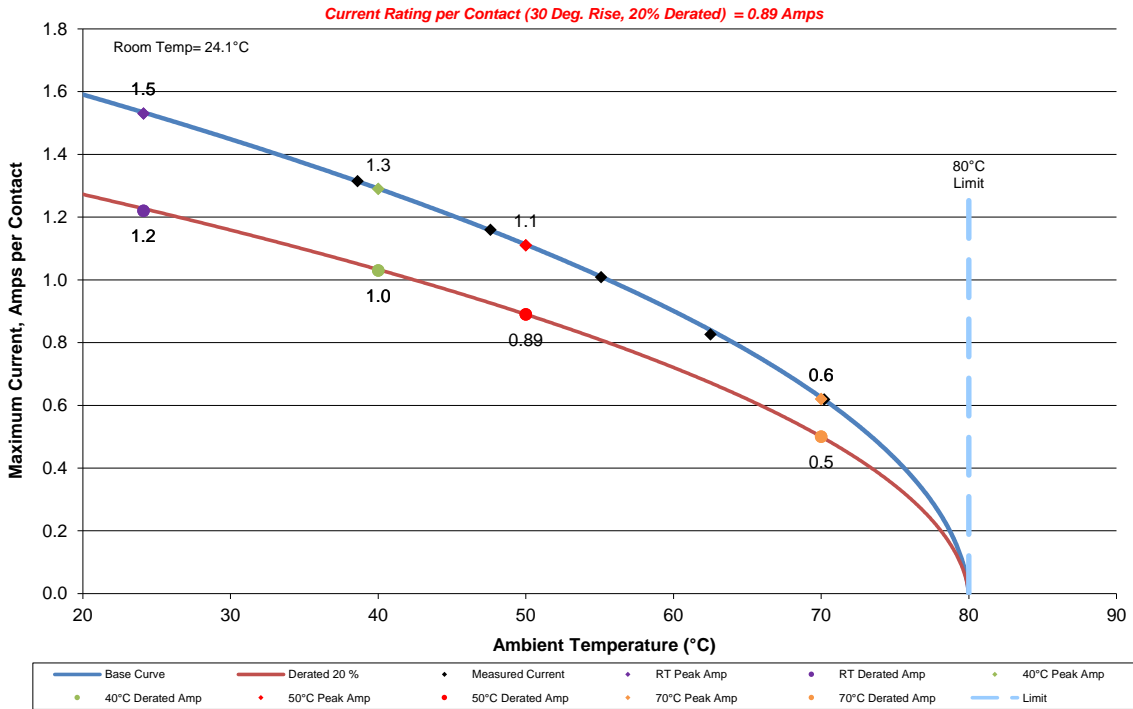
CR-980401
 4(2X2) Contacts in Series(Signal Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



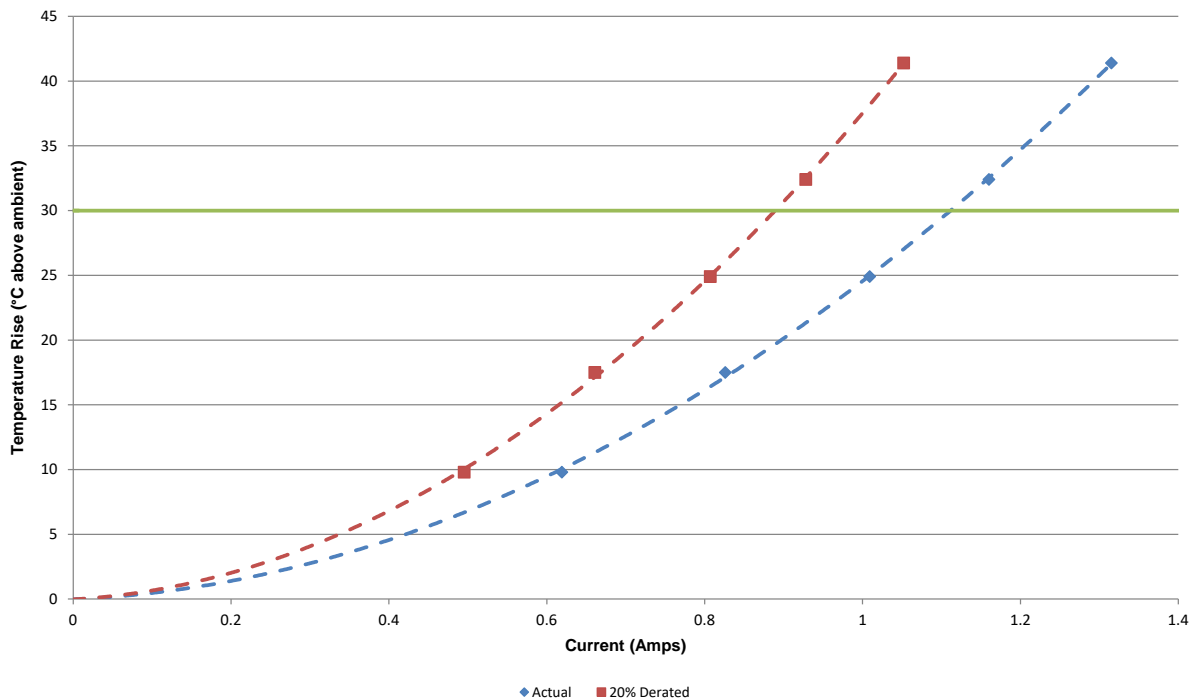
DATA SUMMARIES Continued

c. Linear configuration with 6 adjacent conductors/contacts powered.

CR-980401
6(2X3) Contacts in Series(Signal Pin Cable)
Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



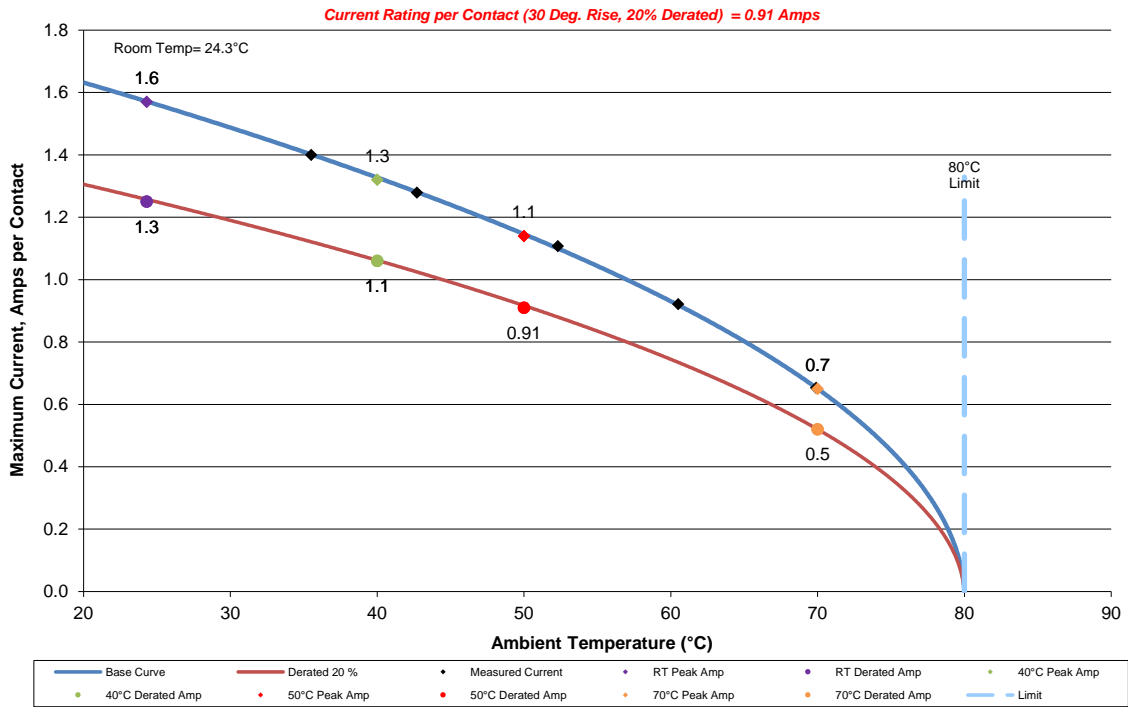
CR-980401
6(2X3) Contacts in Series(Signal Pin Cable)
Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



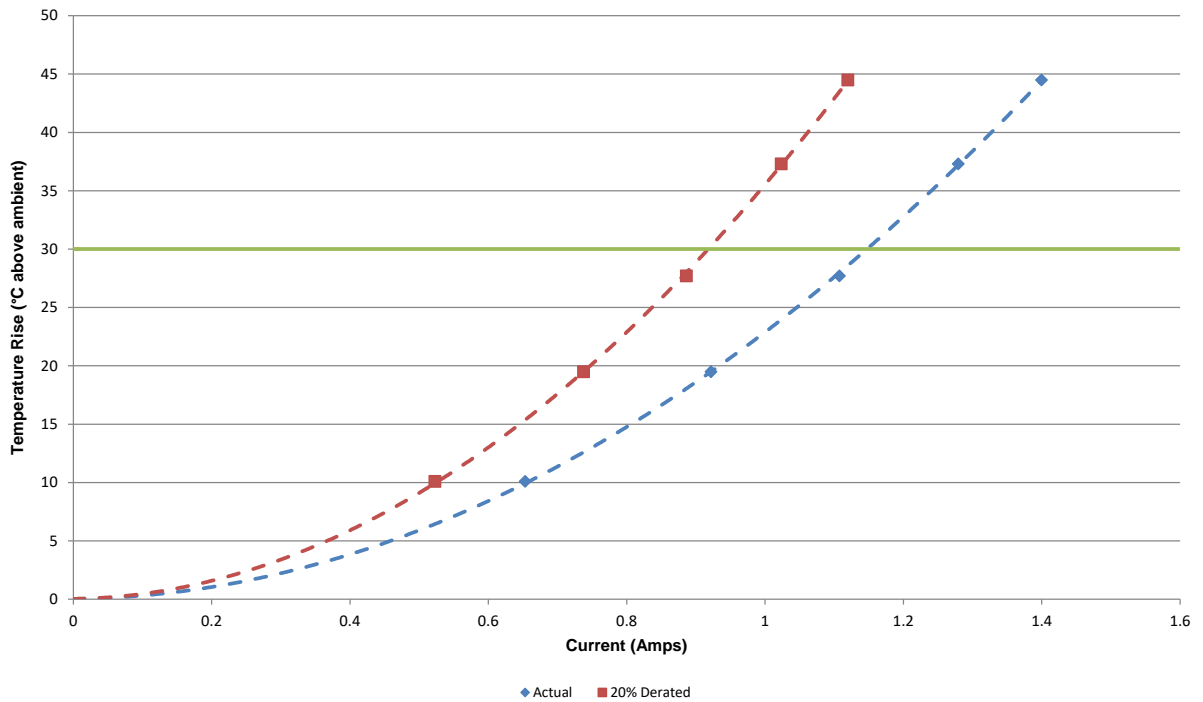
DATA SUMMARIES Continued

d. Linear configuration with 8 adjacent conductors/contacts powered.

CR-980401
 8(2X4) Contacts in Series(Signal Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



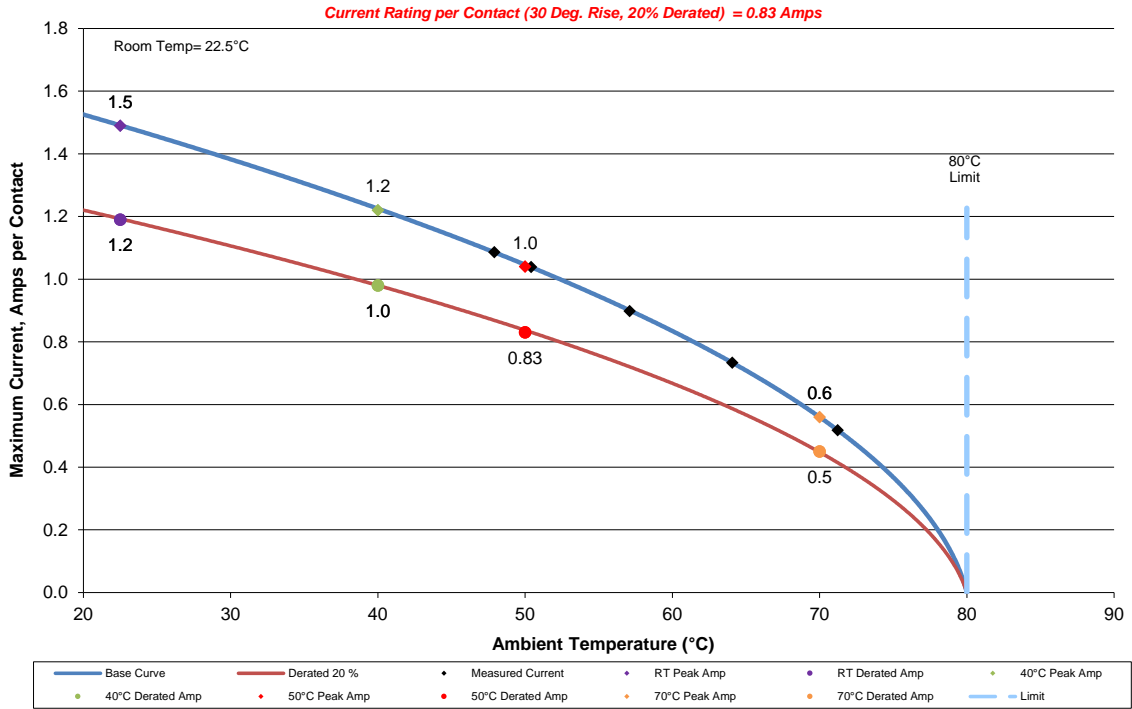
CR-980401
 8(2X4) Contacts in Series(Signal Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



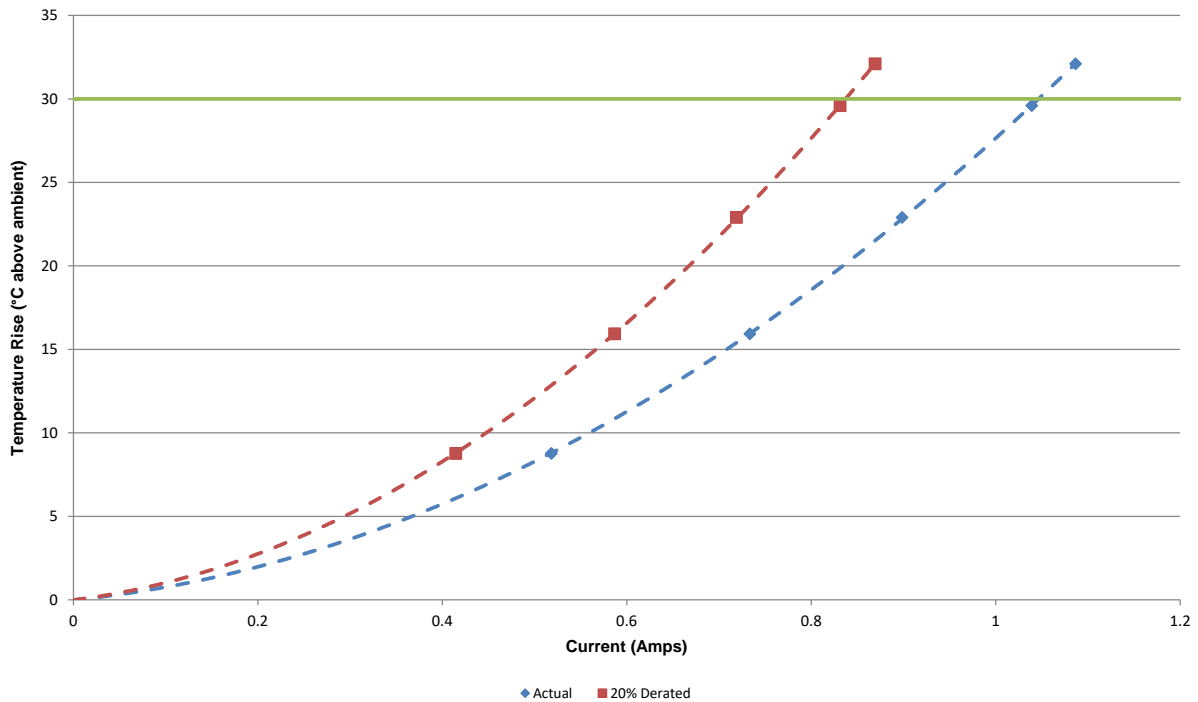
DATA SUMMARIES Continued

e. Linear configuration with all adjacent conductors/contacts powered.

CR-980401
 66(2X33) Contacts in Series(Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



CR-980401
 66(2X33) Contacts in Series(Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT

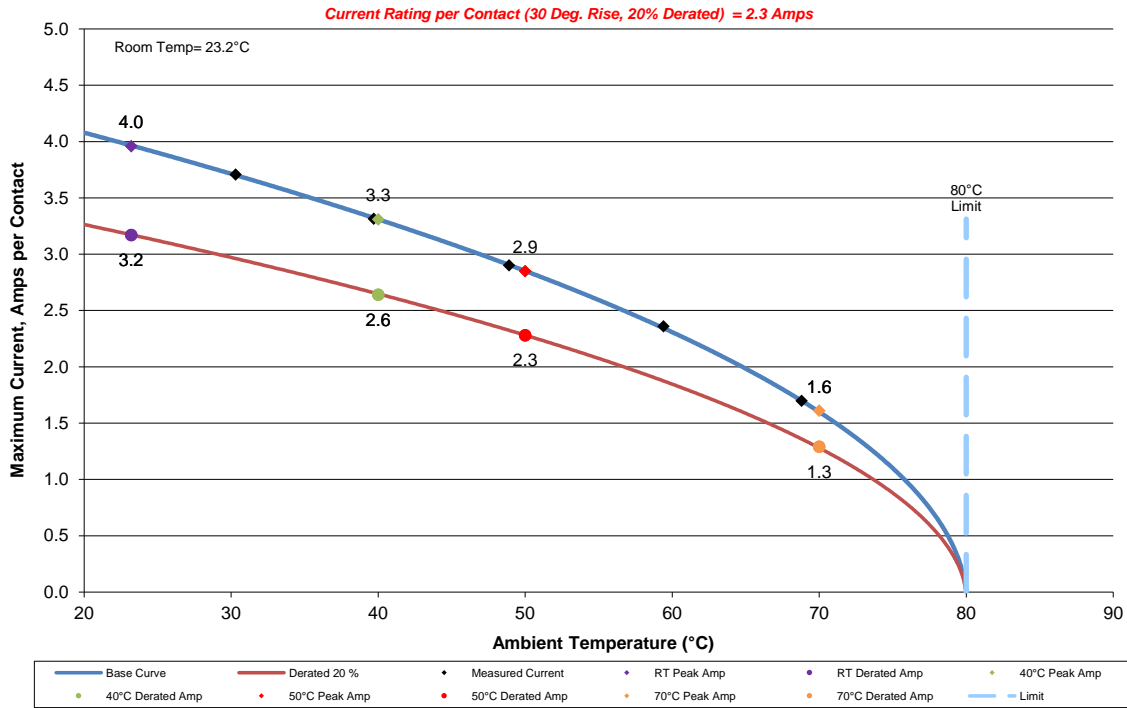


DATA SUMMARIES Continued

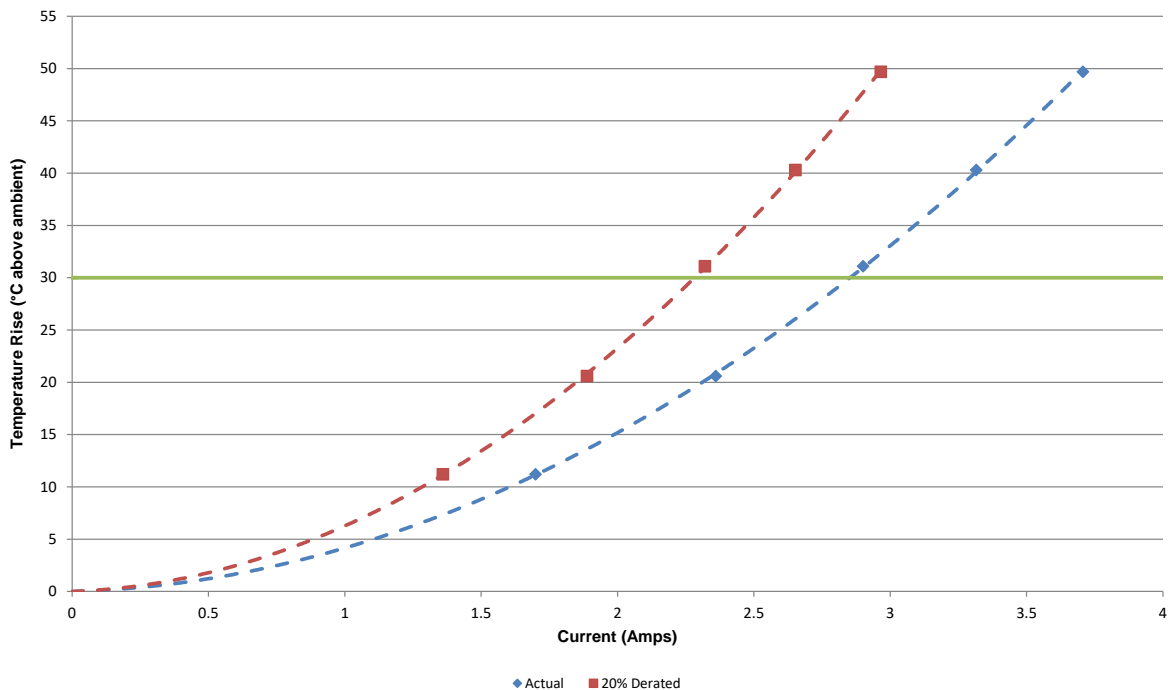
Power Pin at Cable

a. Linear configuration with 2 adjacent conductors/contacts powered.

CR-980401
 2(2X1) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



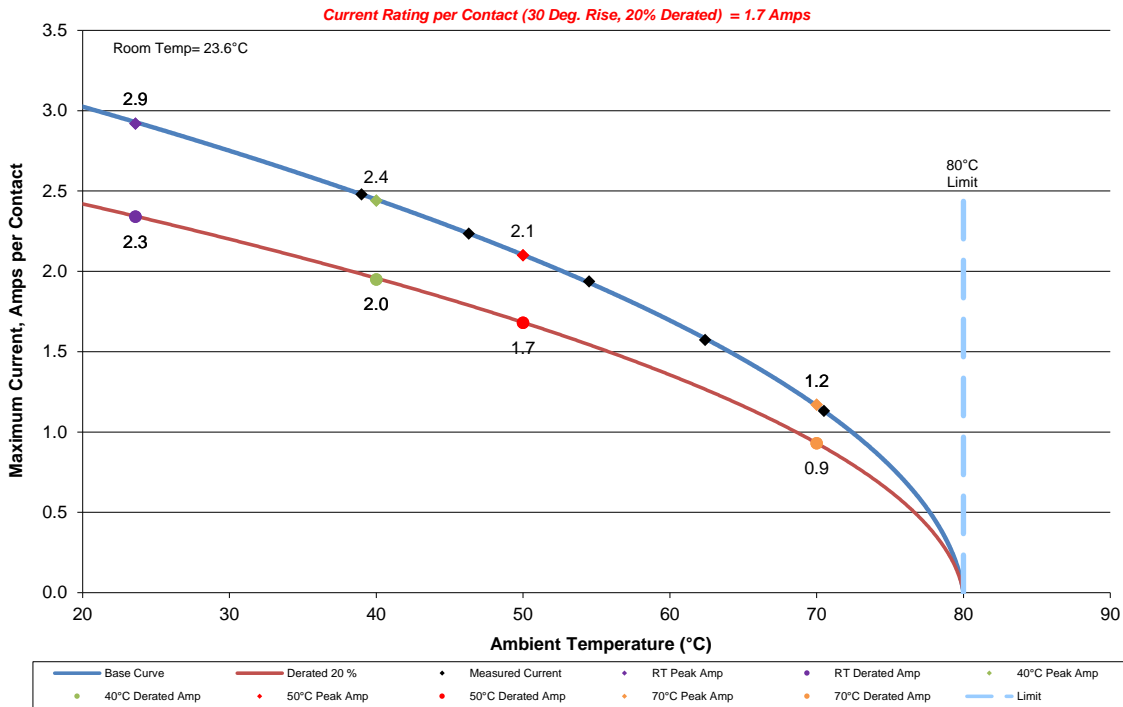
CR-980401
 2(2X1) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



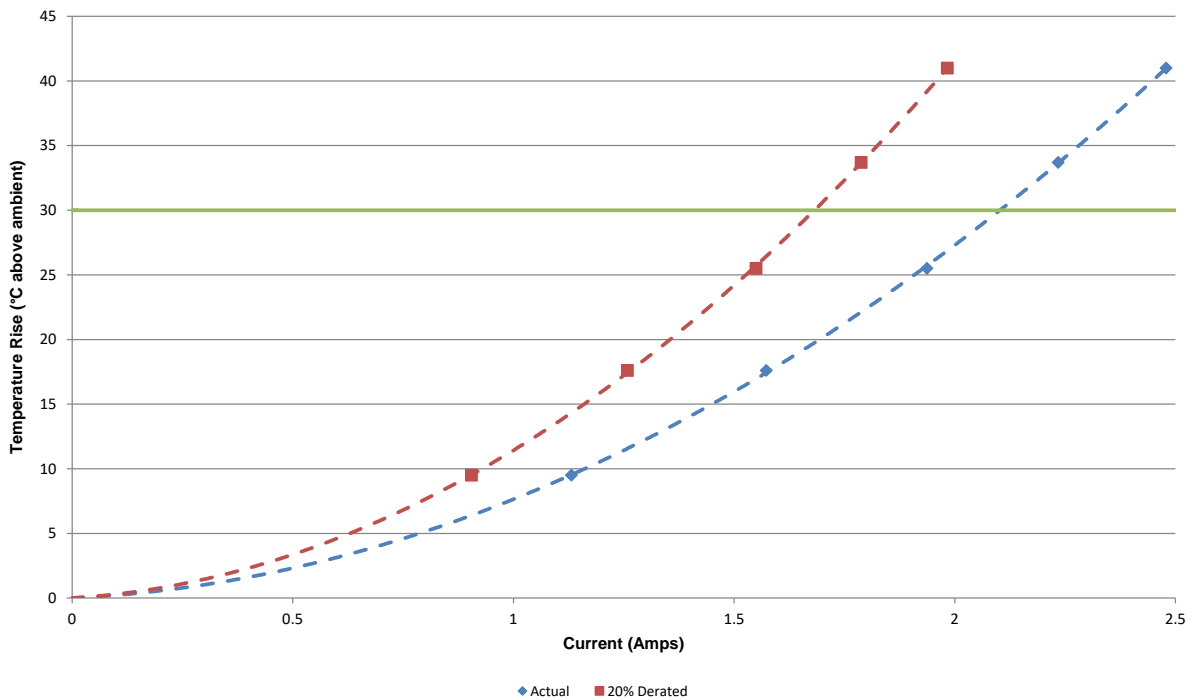
DATA SUMMARIES Continued

b. Linear configuration with 4 adjacent conductors/contacts powered.

CR-980401
 4(2X2) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



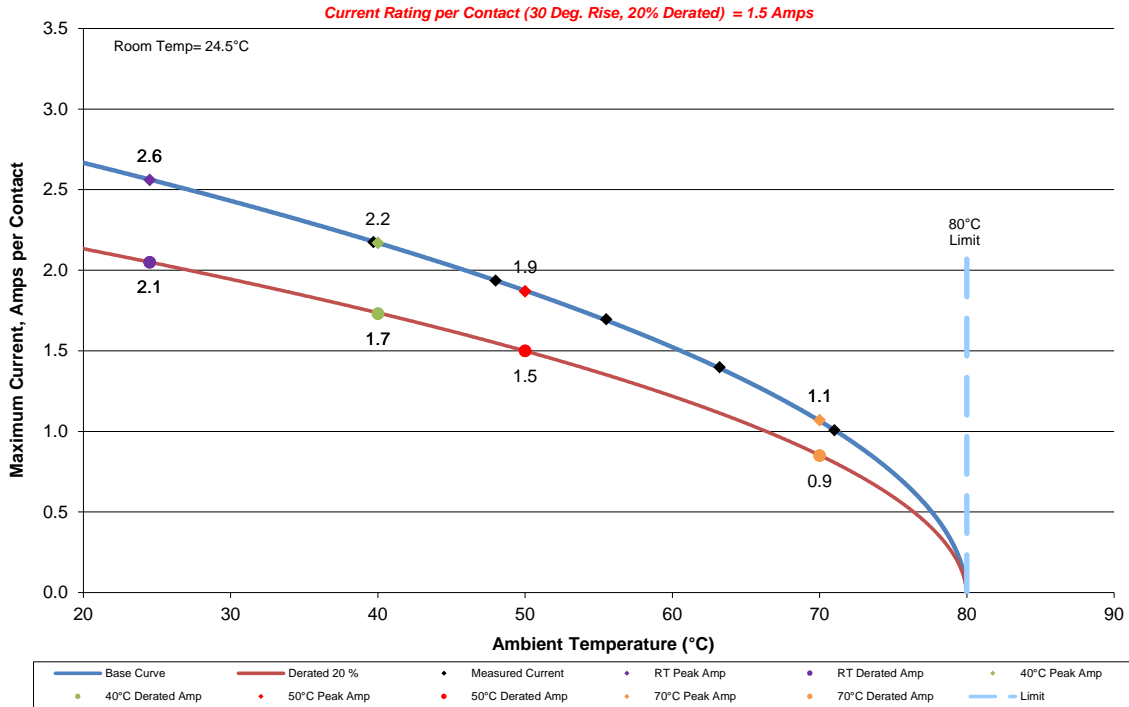
CR-980401
 4(2X2) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



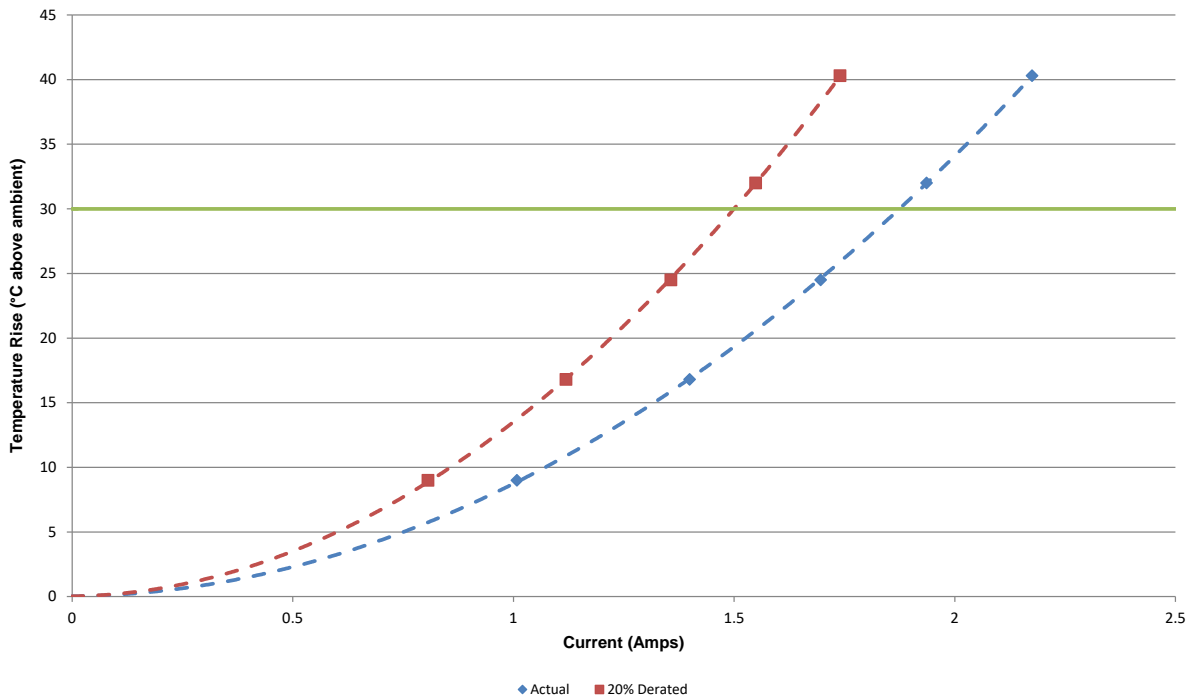
DATA SUMMARIES Continued

c. Linear configuration with 6 adjacent conductors/contacts powered.

CR-980401
 6(2X3) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



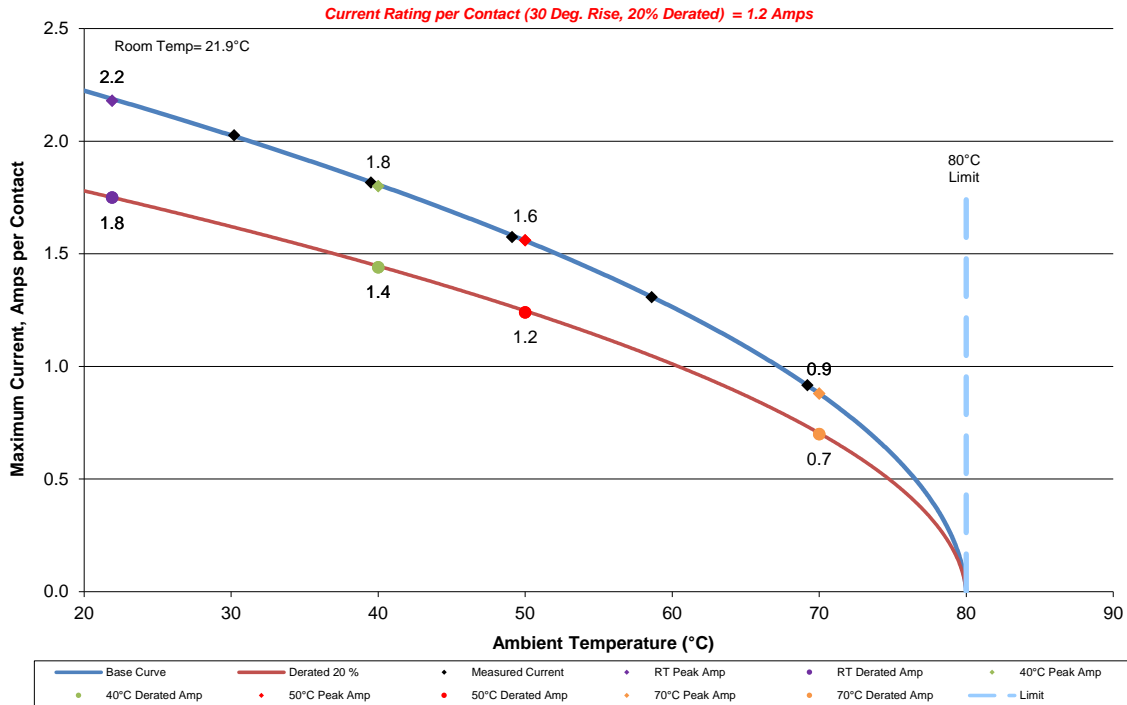
CR-980401
 6(2X3) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



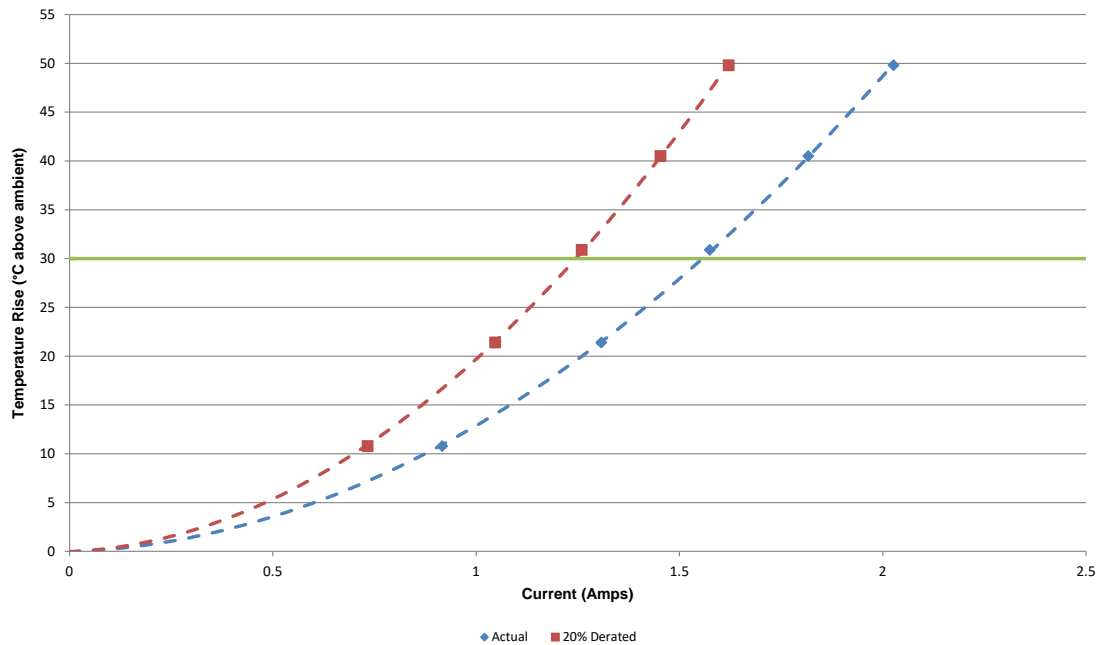
DATA SUMMARIES Continued

d. Linear configuration with 8 adjacent conductors/contacts powered.

CR-980401
 8(2X4) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



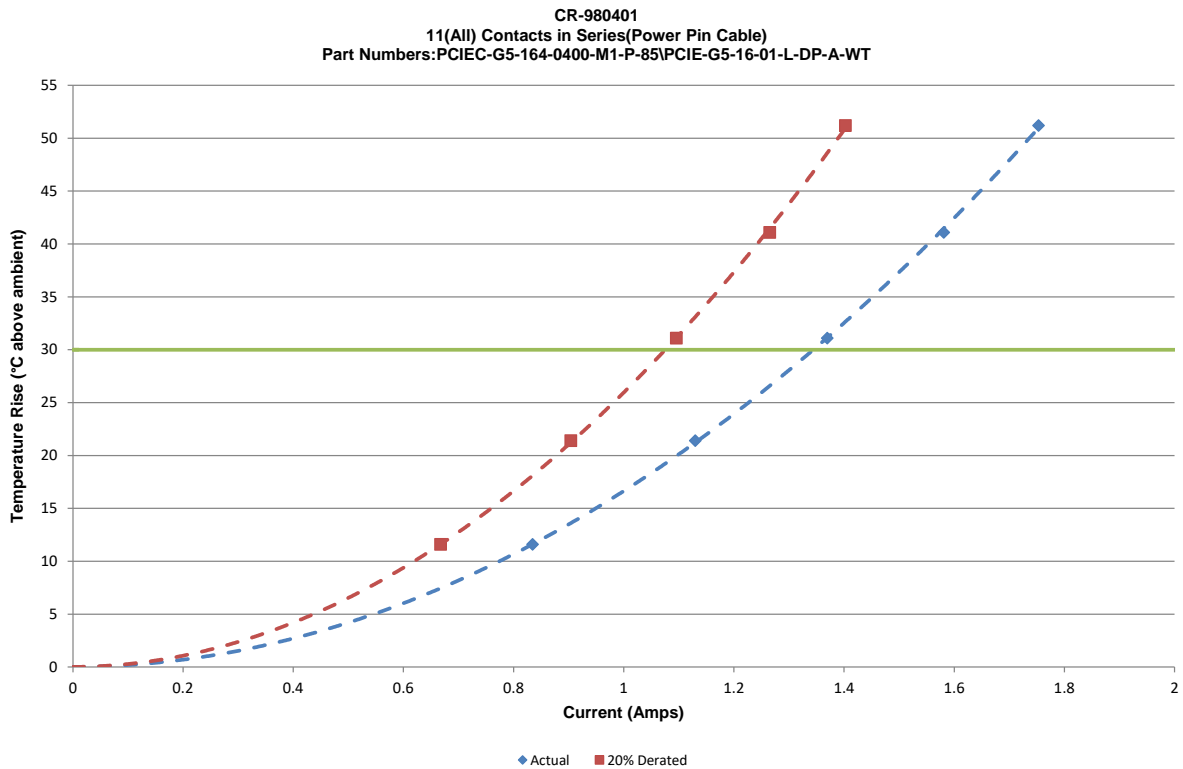
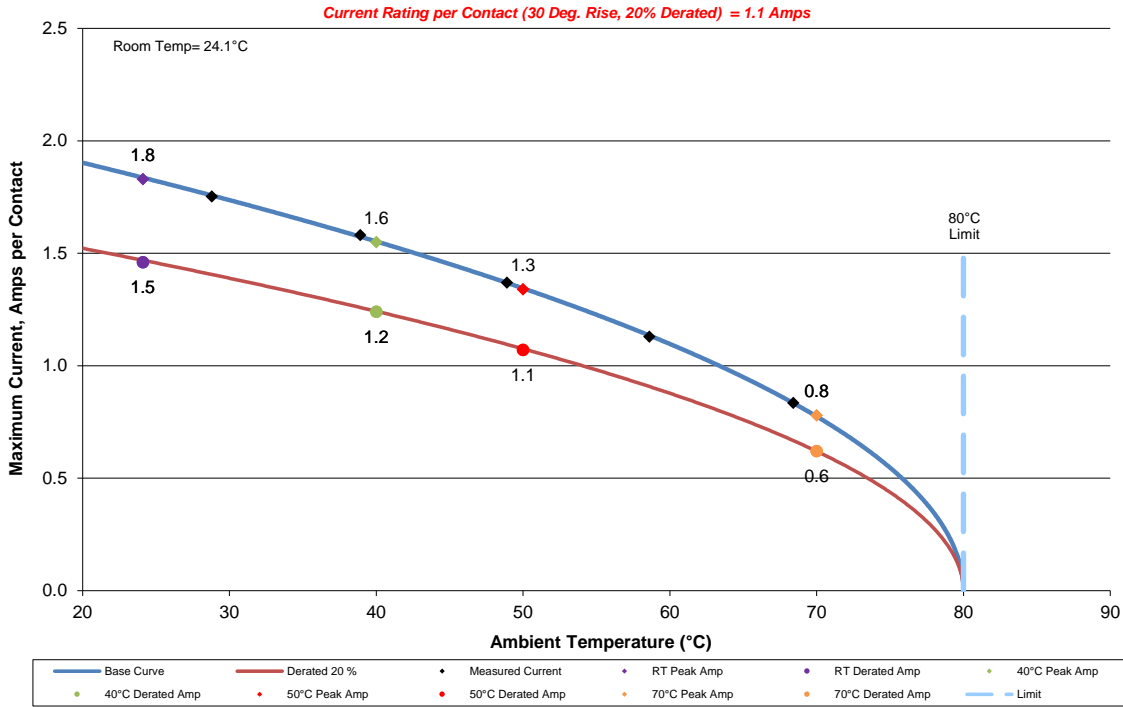
CR-980401
 8(2X4) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



DATA SUMMARIES Continued

e. Linear configuration with all adjacent conductors/contacts powered.

CR-980401
 11(All) Contacts in Series(Power Pin Cable)
 Part Numbers:PCIEC-G5-164-0400-M1-P-85\PCIE-G5-16-01-L-DP-A-WT



DATA SUMMARIES Continued**Cable Pull Force:
90° Pull****PCIEC-G5-164-0400-M1-P-85**

| | Force (lbs) |
|---------|---------------|
| Minimum | 254.45 |
| Maximum | 267.67 |
| Average | 261.57 |

PCIEC-G5-036-0400-M1-P-85

| | Force (lbs) |
|---------|--------------|
| Minimum | 62.80 |
| Maximum | 66.72 |
| Average | 65.53 |

PCIEC-G5-064-0400-M1-P-85

| | Force (lbs) |
|---------|---------------|
| Minimum | 105.60 |
| Maximum | 116.79 |
| Average | 113.25 |

DATA SUMMARIES Continued**INSULATION RESISTANCE (IR):**

| | Pin to Pin | | |
|----------|---------------|----------|---------|
| | Mated | Unmated | Unmated |
| Minimum | PCIEC-G5/PCIE | PCIEC-G5 | PCIE |
| Initial | 45000 | 45000 | 45000 |
| Thermal | 45000 | 45000 | 45000 |
| Humidity | 45000 | 45000 | 45000 |

| | Row to Row | | |
|----------|---------------|----------|---------|
| | Mated | Unmated | Unmated |
| Minimum | PCIEC-G5/PCIE | PCIEC-G5 | PCIE |
| Initial | 45000 | 45000 | 45000 |
| Thermal | 45000 | 45000 | 45000 |
| Humidity | 45000 | 45000 | 45000 |

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

| Voltage Rating Summary | |
|------------------------|---------------|
| Minimum | PCIEC-G5/PCIE |
| Break Down Voltage | 905 |
| Test Voltage | 680 |
| Working Voltage | 225 |

| Pin to Pin | |
|-----------------------------|--------|
| Initial Test Voltage | Passed |
| After Thermal Test Voltage | Passed |
| After Humidity Test Voltage | Passed |

| Row to Row | |
|-----------------------------|--------|
| Initial Test Voltage | Passed |
| After Thermal Test Voltage | Passed |
| After Humidity Test Voltage | Passed |

DATA SUMMARIES Continued**Cable Flex:****Insulation Resistance minimums, IR**

| Pin to Pin | |
|------------------------------|-------|
| Mated | |
| Minimum | |
| Initial | 21500 |
| After 500 Flex Cycles | 34000 |
| Row to Row | |
| Mated | |
| Minimum | |
| Initial | 45000 |
| After 500 Flex Cycles | 45000 |

Dielectric Withstanding Voltage minimums, DWV

| Voltage Rating Summary | |
|---|----------------------|
| Minimum | PCIEC-G5/PCIE |
| Test Voltage | 680 |
| Pin to Pin | |
| Initial Test Voltage | Passed |
| After 500 Flex Cycles Test Voltage | Passed |
| Row to Row | |
| Initial Test Voltage | Passed |
| After 500 Flex Cycles Test Voltage | Passed |

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** HZ-TCT-01**Description:** Normal force analyzer**Manufacturer:** Mecmesin Multitester**Model:** Mecmesin Multitester 2.5-i**Serial #:** 08-1049-04**Accuracy:** Last Cal: 3/5/2023, Next Cal: 3/4/2024**Equipment #:** DG-THC-01**Description:** Humidity transmitter**Manufacturer:** Thermtron**Model:** SM-8-8200**Serial #:** 50613**Accuracy:** Last Cal: 12/4/2023, Next Cal: 12/3/2024**Equipment #:** HZ-TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14994**Accuracy:** See Manual

... Last Cal: 04/16/2023, Next Cal: 04/15/2024

Equipment #: DG-HPT-01**Description:** Hipot Safety Tester**Manufacturer:** Vitrek**Model:** V73**Serial #:** 025866**Accuracy:**

... Last Cal: 04/16/2023, Next Cal: 04/15/2024

Equipment #: HZ-MO-05**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 1285188**Accuracy:** Last Cal: 1/2/2023, Next Cal: 1/1/2024**Equipment #:** HZ-MO-01**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 2700**Serial #:** 1199807**Accuracy:** Last Cal: 05/19/2023, Next Cal: 05/18/2024**Equipment #:** HZ-PS-01**Description:** Power Supply**Manufacturer:** Agilent**Model:** 6031A**Serial #:** MY41000982**Accuracy:** Last Cal: 04/16/2023, Next Cal: 04/15/2024